

<b>Notice of References Cited</b>	Application/Control No. 10/721,455	Applicant(s)/Patent Under Reexamination VAN DER MEER ET AL.	
	Examiner Marcus Charles	Art Unit 3682	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,655,732	04-1987	Takashima, Takashi	474/201
*	B	US-6,283,882	09-2001	Nonaka et al.	474/242
*	C	US-6,500,086	12-2002	Serkh et al.	474/245
*	D	US-6,599,211	07-2003	Sattler, Heiko	474/242
*	E	US-6,634,975	10-2003	Yuan, Jing	474/242
*	F	US-6,679,798	01-2004	Takagi et al.	474/242
*	G	US-6,857,980	02-2005	van Liempd et al.	474/242
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP (04-83941) A	03-1992	Japan	Yamada	F16g 5/16
	O	JP (62-137445) A	06-1987	Japan	---	F16G 5/16
	P	JP (63-280946) A	11-1988	Japan	Kino et al.	474/242
	Q	JP (20002-168306) A	06-2002	Japan	Tawara et al.	F16G 5/16
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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